

Search Notes

Application/Control No.

09/782,816

Examiner

Christopher H. Yaen

Applicant(s)/Patent under
Reexamination

SHARP ET AL.

Art Unit

1643

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Stic seq searches : SEQ ID No: 3+1+22; SEQ ID No: 51	2/3/2006	CHY
palm inventor search	2/3/2006	CHY
West- enclosed	2/3/2006	CHY